



BAMFIT Bonder / Tester 5600

Test System

| | |
|-----------------------|--|
| Test Head | The proprietary clamping tool grips the bond foot from the sides and at a defined height; a touchdown system automatically compensates height variations in the substrate |
| Test Tool | for Al heavy wires from 125 to 400 µm; user-exchangeable within minutes |
| Test Time | 1 test < 1 minute |
| Test Force | Pull force in Z direction, typically 20 to 50 cN |
| Test Frequency | 60 and 80 kHz, programmable Ultrasonic Generator |
| Test Amplitude | Corresponds to temperature swing in PC test; programmable between 0 and 1 µm |
| Test Data | Tool position, ultrasonic data,... are registered continuously and stored in a database for subsequent evaluation. Statistics and analysis can easily be done with the CSR (Corporate Standard Report) software. |

BAMFIT-Tester

The revolutionary **BAMFIT test** can easily be implemented on every base unit of the 56XX series by installing a dedicated test head.

The software is closely related to the standard versions for bonders and testers. It is capable of fully automatic testing of any number of bonds, employing automatic adjustments by pattern recognition.

Test results are recorded in a database. Statistics and analysis can easily be done with the CSR (Corporate Standard Report) Software

BAMFIT Reliability Test

BAMFIT (Bond Accelerated Mechanical Fatigue Interconnection Test) is an entirely novel test method for assessing the reliability of heavy-wire wedge bonds. It is the perfect extension of the classic power cycling test (PC): the cyclic stress imparted to the wire bond by temperature changes is emulated by mechanical stress loading, but at a significantly higher cycle rate. This allows PC tests that can take weeks or months to be simulated within minutes.

The patent-pending BAMFIT tester thus permits a qualitative estimate of the lifetime and reliability of wire bonds, either as process diagnostics or for optimizing bond process parameters.

Machine Base

| | |
|--------------------|---|
| Work Area | X/Y axes 100x100 mm / Z axis 60 mm |
| Axes | Step resolution 0,25 µm; Repeatability <2 µm |
| Test Head | User-exchangeable bond and test heads with automatic identification |
| Hardware | Dual-Core PC with Windows OS Ethernet, USB 2.0/3.0, LCD Color display 22" GigE-CMOS-Color camera Network compatible with program archiving |
| Software | Manual or automatic measurements of any number of bonds CAD data import for easier programming |
| Dimensions | B x T x H – 70 x 65 x 70 cm, weight ca. 80 kg |
| Connections | 100-240 VAC, single phase, 50/60 Hz, max. 500 VA Standard vacuum tube Ø 6 mm |

F&S Bondtec Semiconductor GmbH

Industriezeile 49a
A-5280 Braunau am Inn
Tel.: +43-7722-67052-8270
Fax: +43-7722-67052-8272
Mail: info@fsbondtec.at
Web: www.fsbondtec.at

